

**GUJARAT TECHNOLOGICAL UNIVERSITY****BE - SEMESTER-VII (NEW) EXAMINATION – WINTER 2018****Subject Code: 2172109****Date: 29/11/2018****Subject Name: Materials Characterization****Time: 10:30 AM TO 01:00 PM****Total Marks: 70****Instructions:**

1. Attempt all questions.
2. Make suitable assumptions wherever necessary.
3. Figures to the right indicate full marks.

		MARKS
<b>Q.1</b>	(a) What do you mean by thermal analysis? Give its significance.	<b>03</b>
	(b) Describe the importance of Material characterization.	<b>04</b>
	(c) Draw schematic showing basic components of the scanning electron microscope. Briefly explain each component and its working in SEM.	<b>07</b>
<b>Q.2</b>	(a) Give the difference between Heat flux DSC and Power Compensated DSC.	<b>03</b>
	(b) "DSC is widely used in industrial settings as a quality control instrument". Comment.	<b>04</b>
	(c) Explain the principle and instrumentation of Diffusion pumps with their merits, limitations and applications.	<b>07</b>
<b>OR</b>		
	(c) What do you mean by Vacuum gauge? Explain the principle and instrumentation of Ionization gauge with their merits, limitations and applications.	<b>07</b>
<b>Q.3</b>	(a) Explain how electron microscopy differs from optical microscopy?	<b>03</b>
	(b) What is Image Analysis? List the steps for microstructural study by image analysis.	<b>04</b>
	(c) Define Magnification of Microscope. Explain Hot Stage Microscopy.	<b>07</b>
<b>OR</b>		
<b>Q.3</b>	(a) Explain resolution of Microscope using the formula.	<b>03</b>
	(b) Describe the principle of Differential Interference Contrast (DIC) microscopy.	<b>04</b>
	(c) Write a note on High Resolution Electron Microscopy (HREM).	<b>07</b>
<b>Q.4</b>	(a) Discuss the advantages and disadvantages of powder diffraction method.	<b>03</b>
	(b) Explain how polished cast iron sample can be studied Using ESCA.	<b>04</b>
	(c) What do you mean by AFM? Explain the principle and instrumentation. Give merits, limitations and applications.	<b>07</b>
<b>OR</b>		
<b>Q.4</b>	(a) Discuss merits, limitations and applications of STM.	<b>03</b>
	(b) Explain the principle and instrumentation of STM.	<b>04</b>
	(c) Compare X-ray Photoelectron Spectroscopy and Auger Electron Spectroscopy techniques.	<b>07</b>
<b>Q.5</b>	(a) What is Raman Effect? How it arises?	<b>03</b>
	(b) With a neat sketch explain IR Spectrometer.	<b>04</b>
	(c) What is XRF? With a block diagram explain the working of XRF system.	<b>07</b>

**OR**

- Q.5** (a) Write applications and limitations of Rutherford backscattering spectroscopy. **03**
- (b) Explain the Secondary Ion mass spectrometry (SIMS). **04**
- (c) Explain briefly Laue method of diffraction. What are the advantages and disadvantages of Laue method? **07**

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